

Product Change Notification: MFOL-300MBY736

Date:

31-Jan-2025

Product Category:

Ethernet Phys

Notification Subject:

CCB 7393 Initial Notice: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 3280NP as a new die attach material for selected KSZ8051, KSZ8081, and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package at MTAI assembly site.

Affected CPNs:

MFOL-300MBY736_Affected_CPN_01312025.pdf MFOL-300MBY736 Affected CPN 01312025.csv

PCN Status: Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 3280NP as a new die attach material for selected KSZ8051, KSZ8081, and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package at MTAI assembly site.

Pre and Post Summary Changes:

	Pre Change	Post Change
Assembly Site	Microchip Technology Thailand (HQ) (MTAI)	Microchip Technology Thailand (HQ) (MTAI)

Wire Material	Au	CuPdAu 3280NP			
Die Attach Material	3280				
Molding Compound Material	G700LTD	G700LTD			
Lead frame Material	A194	A194			

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve productivity by qualifying palladium coated copper with gold flash

(CuPdAu) as a new bond wire material and 3280NP as a new die attach material.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: March 2025

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Timetable Summary:

	February 2025					March 2025					
Work Week	05	06	07	08	09	10	11	12	13	14	
Initial PCN Issue Date		Х									
Qual Report Availability										Χ	
Final PCN Issue Date										Х	

Method to Identify Change: Traceability Code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History: February 04, 2025: Issued initial notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_MFOL-300MBY736_Qual Plan.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to <u>change your PCN profile, including opt out,</u> please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

MFOL-30OMBY736 - CCB 7393 Initial Notice: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 3280NP as a new die attach material for selected KSZ8051, KSZ8081, and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package at MTAI assembly site.

Affected Catalog Part Numbers (CPN)

KSZ8081MNXCA

KSZ8081MNXIA

KSZ8091MNXCA

KSZ8091RNBCA

SPNZ801174

KSZ8081RNBCA-TR

KSZ8091RNBCA-TR

KSZ8081MNXCA-TR

KSZ8091MNXCA-TR

KSZ8081MNXIA-TR

KSZ8091MNXIA-TR

KSZ8081RNBIA-TR

KSZ8091RNBIA-TR

KSZ8051RNLV

KSZ8051RNLV-TR

Date: Friday, January 31, 2025



QUALIFICATION PLAN SUMMARY

PCN #: MFOL-300MBY736

Date: January 30, 2025

Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 3280NP as a new die attach material for selected KSZ8051, KSZ8081, and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package at MTAI assembly site.

Purpose: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 3280NP as a new die attach material for selected KSZ8051, KSZ8081, and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package at MTAI assembly site.

CCB No.: 7393

	Assembly site	MTAI				
	BD Number	BD-002990				
Misc.	MP Code (MPC)	XKAA1TPFAA14				
	Part Number (CPN)	KSZ8081RNBIA-TR				
	MSL information	MSL-2				
	Assembly Shipping Media (T/R, Tube/Tray)	T/R				
	Base Quantity Multiple (BQM)	1000				
	Reliability Site	MTAI				
	Paddle size	150 x 150				
	Material	A194				
	DAP Surface Prep	Ag selective				
	Treatment	Roughened				
<u>Lead</u>	Process	Etched				
<u>Frame</u>	Lead-lock (Locking Hole, Half Etched, Dimple, etc. If none, please put No or N/A)	Yes				
	Part Number	10103214				
	Lead Plating	Matte tin				
Bond Wire	Material	CuPdAu				
Die Attach	Part Number	3280NP				
Die Attach	Conductive	Yes				
<u>MC</u>	Part Number	G700LTD				
	Package Type	VQFN				
<u>PKG</u>	Pin/Ball Count	32				
	PKG width/size	5x5				

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL test site	Special Instruction
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5			30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5	0	5			30 bonds from a min. 5 devices.
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5			
HTSL (High Temp Storage Life)	JESD22-A103. +175 C for 504 hours Electrical test pre and post stress at +25C and hot temp 85C.	45	5			0	10	MTAI	MTAI	
Preconditioning - Required for surface mount devices	JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C and 85C. Perform SAM (C-SCAN) analysis using 45 samples per lot.	231	15	3	738	0	15	MTAI	MTAI	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test site	Special Instruction
HAST	JESD22-A110. +130°C/85% RH for 96 hours Electrical test pre and post stress at +25°C and hot temp 85C.	77	5	3	246	0	10	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Preconditioning.
UHAST	JESD22-A118. +130°C/85% RH for 96 hrs Electrical test pre and post stress at +25°C	77	5	3	246	0	10	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Preconditioning.
Temp Cycle	JESD22-A10465°C to +150°C for 500 cycles Electrical test pre and post stress at hot temp 85C; 3-gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.	77	5	3	246	0	15	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.